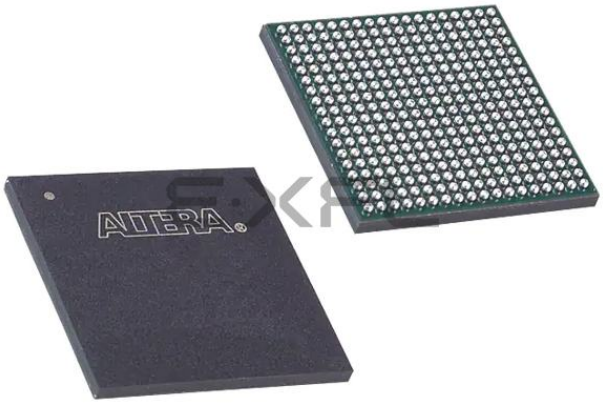

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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

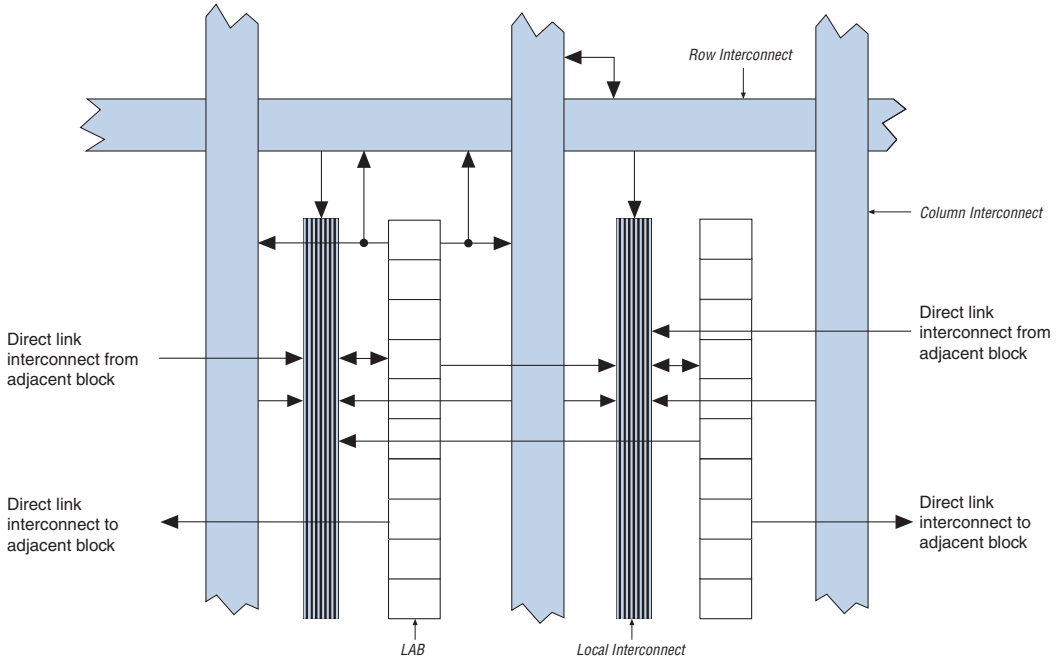
The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Obsolete
Number of LABs/CLBs	1206
Number of Logic Elements/Cells	12060
Total RAM Bits	239616
Number of I/O	249
Number of Gates	-
Voltage - Supply	1.425V ~ 1.575V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	324-BGA
Supplier Device Package	324-FBGA (19x19)
Purchase URL	https://www.e-xfl.com/product-detail/intel/ep1c12f324c7

Logic Array Blocks

Each LAB consists of 10 LEs, LE carry chains, LAB control signals, a local interconnect, look-up table (LUT) chain, and register chain connection lines. The local interconnect transfers signals between LEs in the same LAB. LUT chain connections transfer the output of one LE's LUT to the adjacent LE for fast sequential LUT connections within the same LAB. Register chain connections transfer the output of one LE's register to the adjacent LE's register within a LAB. The Quartus® II Compiler places associated logic within a LAB or adjacent LABs, allowing the use of local, LUT chain, and register chain connections for performance and area efficiency. Figure 2–2 details the Cyclone LAB.

Figure 2–2. Cyclone LAB Structure

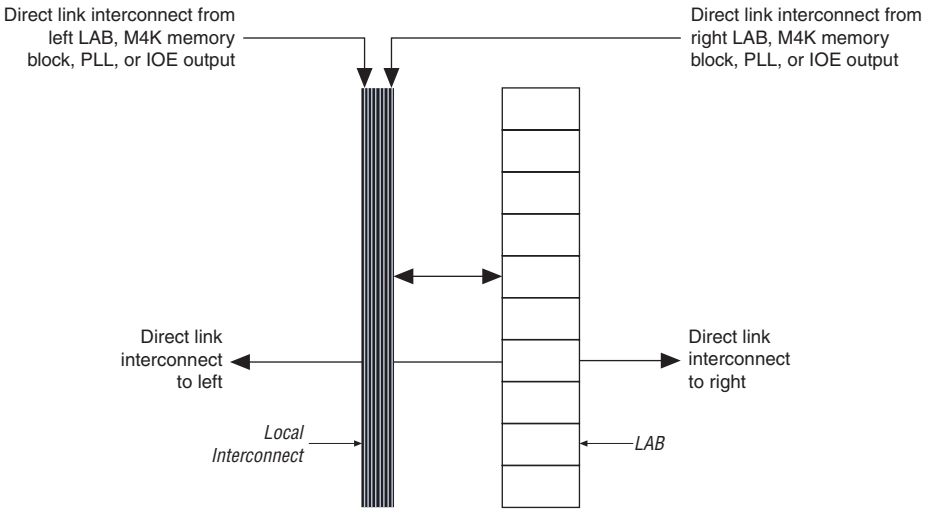


LAB Interconnects

The LAB local interconnect can drive LEs within the same LAB. The LAB local interconnect is driven by column and row interconnects and LE outputs within the same LAB. Neighboring LABs, PLLs, and M4K RAM blocks from the left and right can also drive a LAB's local interconnect through the direct link connection. The direct link connection feature minimizes the use of row and column interconnects, providing higher

performance and flexibility. Each LE can drive 30 other LEs through fast local and direct link interconnects. Figure 2–3 shows the direct link connection.

Figure 2–3. Direct Link Connection



LAB Control Signals

Each LAB contains dedicated logic for driving control signals to its LEs. The control signals include two clocks, two clock enables, two asynchronous clears, synchronous clear, asynchronous preset/load, synchronous load, and add/subtract control signals. This gives a maximum of 10 control signals at a time. Although synchronous load and clear signals are generally used when implementing counters, they can also be used with other functions.

Each LAB can use two clocks and two clock enable signals. Each LAB's clock and clock enable signals are linked. For example, any LE in a particular LAB using the `labclk1` signal will also use `labclkena1`. If the LAB uses both the rising and falling edges of a clock, it also uses both LAB-wide clock signals. Deasserting the clock enable signal will turn off the LAB-wide clock.

Each LAB can use two asynchronous clear signals and an asynchronous load/preset signal. The asynchronous load acts as a preset when the asynchronous load data input is tied high.

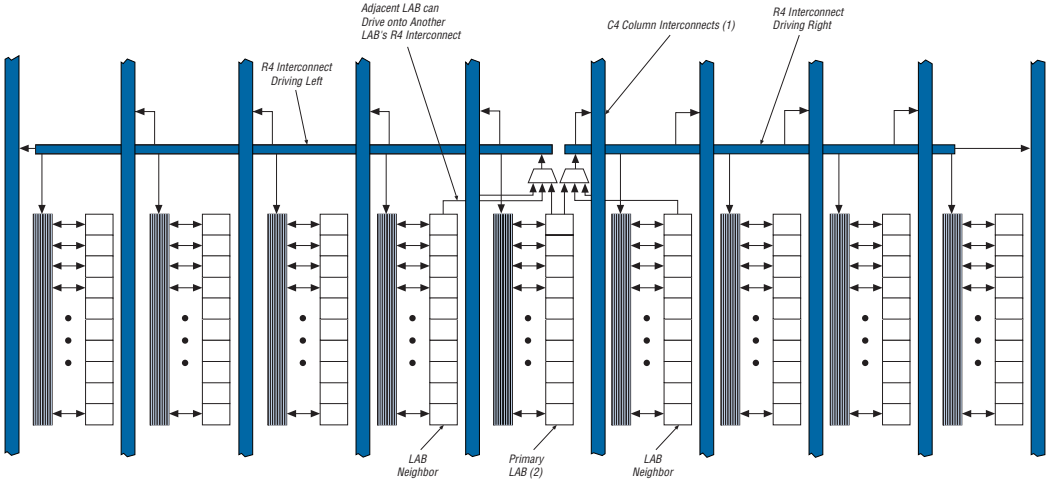
migrating through different device densities. Dedicated row interconnects route signals to and from LABs, PLLs, and M4K memory blocks within the same row. These row resources include:

- Direct link interconnects between LABs and adjacent blocks
- R4 interconnects traversing four blocks to the right or left

The direct link interconnect allows a LAB or M4K memory block to drive into the local interconnect of its left and right neighbors. Only one side of a PLL block interfaces with direct link and row interconnects. The direct link interconnect provides fast communication between adjacent LABs and/or blocks without using row interconnect resources.

The R4 interconnects span four LABs, or two LABs and one M4K RAM block. These resources are used for fast row connections in a four-LAB region. Every LAB has its own set of R4 interconnects to drive either left or right. Figure 2–9 shows R4 interconnect connections from a LAB. R4 interconnects can drive and be driven by M4K memory blocks, PLLs, and row IOEs. For LAB interfacing, a primary LAB or LAB neighbor can drive a given R4 interconnect. For R4 interconnects that drive to the right, the primary LAB and right neighbor can drive on to the interconnect. For R4 interconnects that drive to the left, the primary LAB and its left neighbor can drive on to the interconnect. R4 interconnects can drive other R4 interconnects to extend the range of LABs they can drive. R4 interconnects can also drive C4 interconnects for connections from one row to another.

Figure 2–9. R4 Interconnect Connections



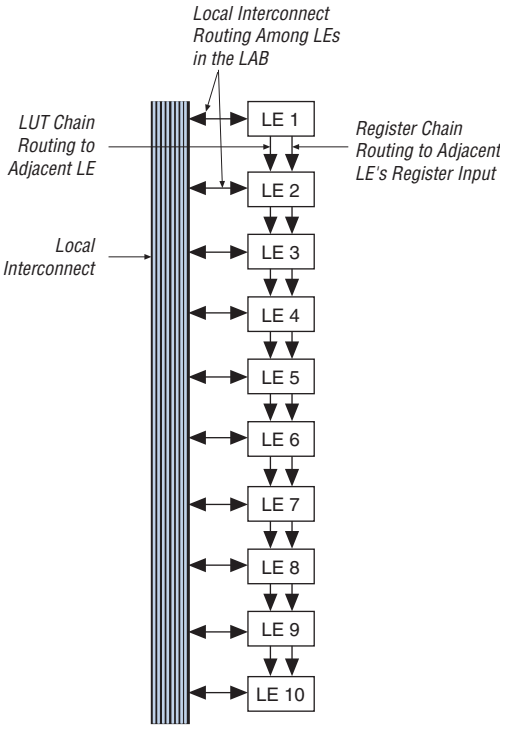
Notes to Figure 2–9:
(1) C4 interconnects can drive R4 interconnects.
(2) This pattern is repeated for every LAB in the LAB row.

The column interconnect operates similarly to the row interconnect. Each column of LABs is served by a dedicated column interconnect, which vertically routes signals to and from LABs, M4K memory blocks, and row and column IOEs. These column resources include:

- LUT chain interconnects within a LAB
- Register chain interconnects within a LAB
- C4 interconnects traversing a distance of four blocks in an up and down direction

Cyclone devices include an enhanced interconnect structure within LABs for routing LE output to LE input connections faster using LUT chain connections and register chain connections. The LUT chain connection allows the combinatorial output of an LE to directly drive the fast input of the LE right below it, bypassing the local interconnect. These resources can be used as a high-speed connection for wide fan-in functions from LE 1 to LE 10 in the same LAB. The register chain connection allows the register output of one LE to connect directly to the register input of the next LE in the LAB for fast shift registers. The Quartus II Compiler automatically takes advantage of these resources to improve utilization and performance. Figure 2–10 shows the LUT chain and register chain interconnects.

Figure 2–10. LUT Chain and Register Chain Interconnects

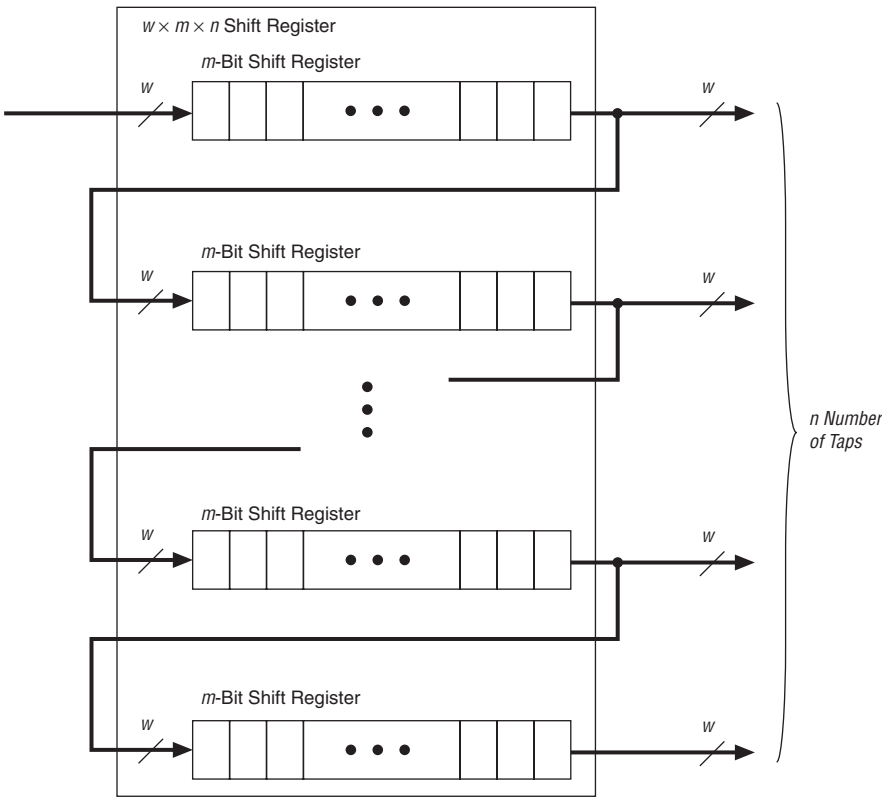


The C4 interconnects span four LABs or M4K blocks up or down from a source LAB. Every LAB has its own set of C4 interconnects to drive either up or down. Figure 2–11 shows the C4 interconnect connections from a LAB in a column. The C4 interconnects can drive and be driven by all types of architecture blocks, including PLLs, M4K memory blocks, and column and row IOEs. For LAB interconnection, a primary LAB or its LAB neighbor can drive a given C4 interconnect. C4 interconnects can drive each other to extend their range as well as drive row interconnects for column-to-column connections.

register outputs (number of taps n × width w) must be less than the maximum data width of the M4K RAM block (×36). To create larger shift registers, multiple memory blocks are cascaded together.

Data is written into each address location at the falling edge of the clock and read from the address at the rising edge of the clock. The shift register mode logic automatically controls the positive and negative edge clocking to shift the data in one clock cycle. Figure 2–14 shows the M4K memory block in the shift register mode.

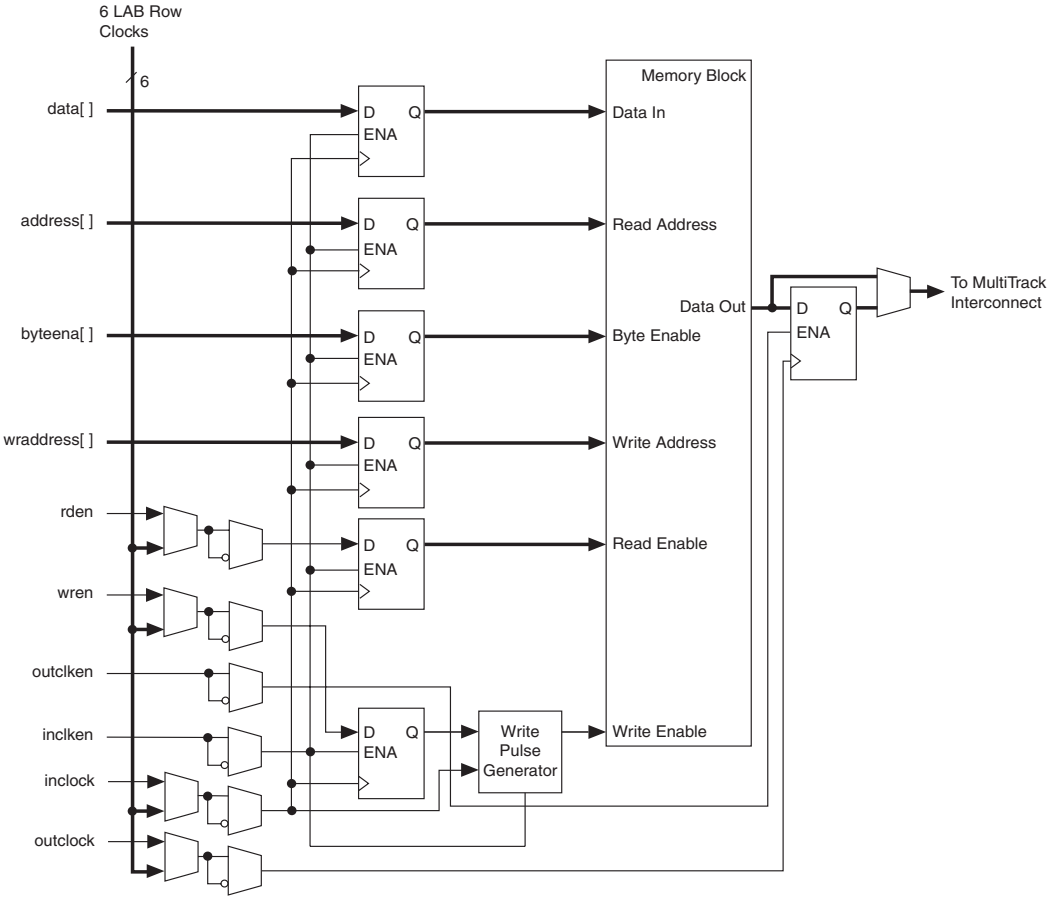
Figure 2–14. Shift Register Memory Configuration



Memory Configuration Sizes

The memory address depths and output widths can be configured as 4,096 × 1, 2,048 × 2, 1,024 × 4, 512 × 8 (or 512 × 9 bits), 256 × 16 (or 256 × 18 bits), and 128 × 32 (or 128 × 36 bits). The 128 × 32- or 36-bit configuration

Figure 2–19. Input/Output Clock Mode in Simple Dual-Port Mode *Notes (1), (2)*



Notes to Figure 2–19:

(1) All registers shown except the rden register have asynchronous clear ports.

(2) Violating the setup or hold time on the address registers could corrupt the memory contents. This applies to both read and write operations.

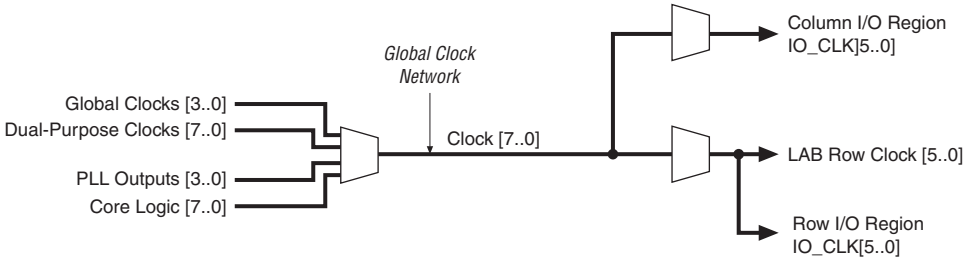
Dual-Purpose Clock Pins

Each Cyclone device except the EP1C3 device has eight dual-purpose clock pins, DPCLK[7..0] (two on each I/O bank). EP1C3 devices have five DPCLK pins in the 100-pin TQFP package. These dual-purpose pins can connect to the global clock network (see Figure 2–22) for high-fanout control signals such as clocks, asynchronous clears, presets, and clock enables, or protocol control signals such as TRDY and IRDY for PCI, or DQS signals for external memory interfaces.

Combined Resources

Each Cyclone device contains eight distinct dedicated clocking resources. The device uses multiplexers with these clocks to form six-bit buses to drive LAB row clocks, column IOE clocks, or row IOE clocks. See Figure 2–23. Another multiplexer at the LAB level selects two of the six LAB row clocks to feed the LE registers within the LAB.

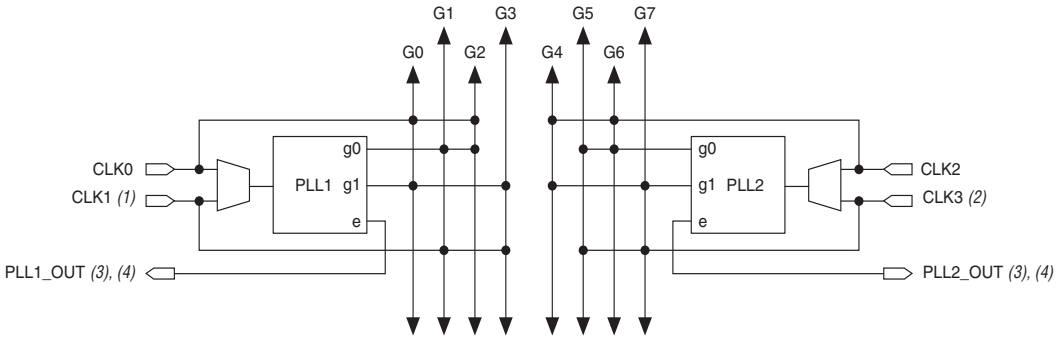
Figure 2–23. Global Clock Network Multiplexers



IOE clocks have row and column block regions. Six of the eight global clock resources feed to these row and column regions. Figure 2–24 shows the I/O clock regions.

Figure 2–26 shows the PLL global clock connections.

Figure 2–26. Cyclone PLL Global Clock Connections



Notes to Figure 2–26:

(1) PLL 1 supports one single-ended or LVDS input via pins CLK0 and CLK1.

(2) PLL2 supports one single-ended or LVDS input via pins CLK2 and CLK3.

(3) PLL1_OUT and PLL2_OUT support single-ended or LVDS output. If external output is not required, these pins are available as regular user I/O pins.

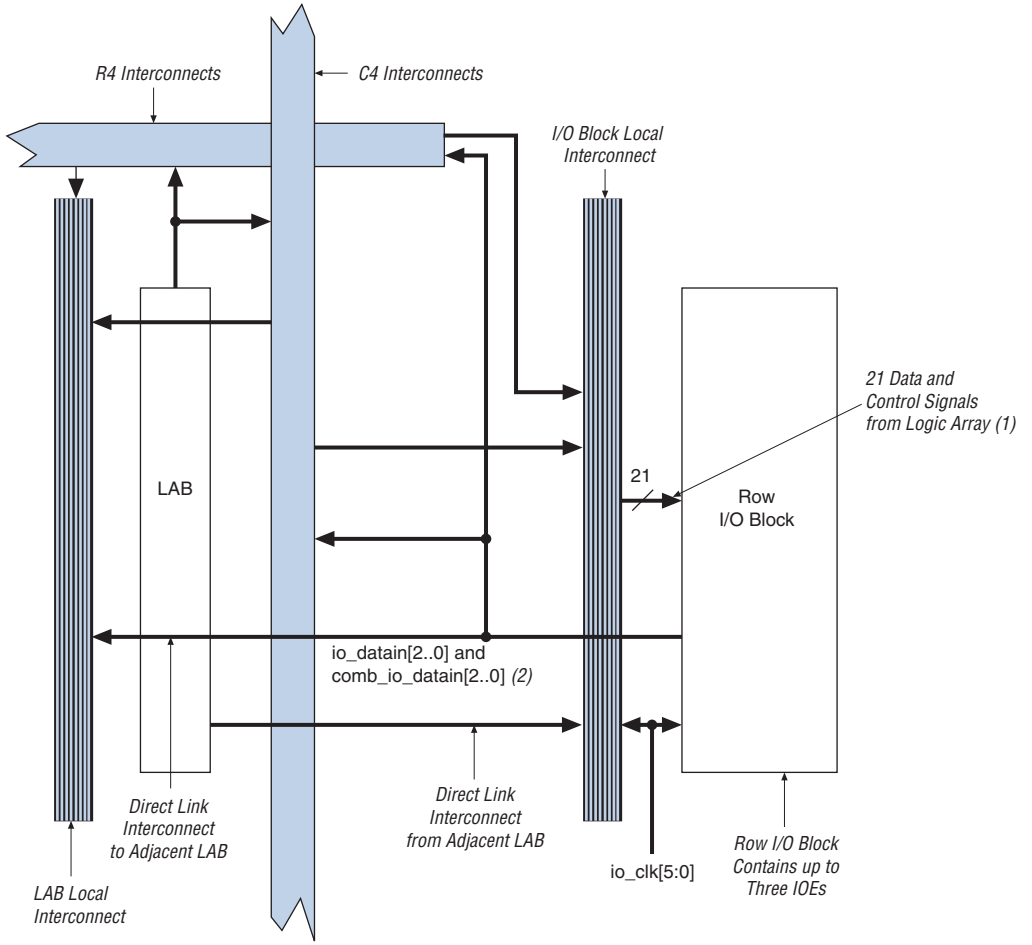
(4) The EP1C3 device in the 100-pin TQFP package does not support external clock output. The EP1C6 device in the 144-pin TQFP package does not support external clock output from PLL2.

Table 2–7 shows the global clock network sources available in Cyclone devices.

Table 2–7. Global Clock Network Sources (Part 1 of 2)

Source		GCLK0	GCLK1	GCLK2	GCLK3	GCLK4	GCLK5	GCLK6	GCLK7
PLL Counter Output	PLL1 G0	—	✓	✓	—	—	—	—	—
	PLL1 G1	✓	—	—	✓	—	—	—	—
	PLL2 G0 *(1)*	—	—	—	—	—	✓	✓	—
	PLL2 G1 *(1)*	—	—	—	—	✓	—	—	✓
Dedicated Clock Input Pins	CLK0	✓	—	✓	—	—	—	—	—
	CLK1 *(2)*	—	✓	—	✓	—	—	—	—
	CLK2	—	—	—	—	✓	—	✓	—
	CLK3 *(2)*	—	—	—	—	—	✓	—	✓

Figure 2–28. Row I/O Block Connection to the Interconnect



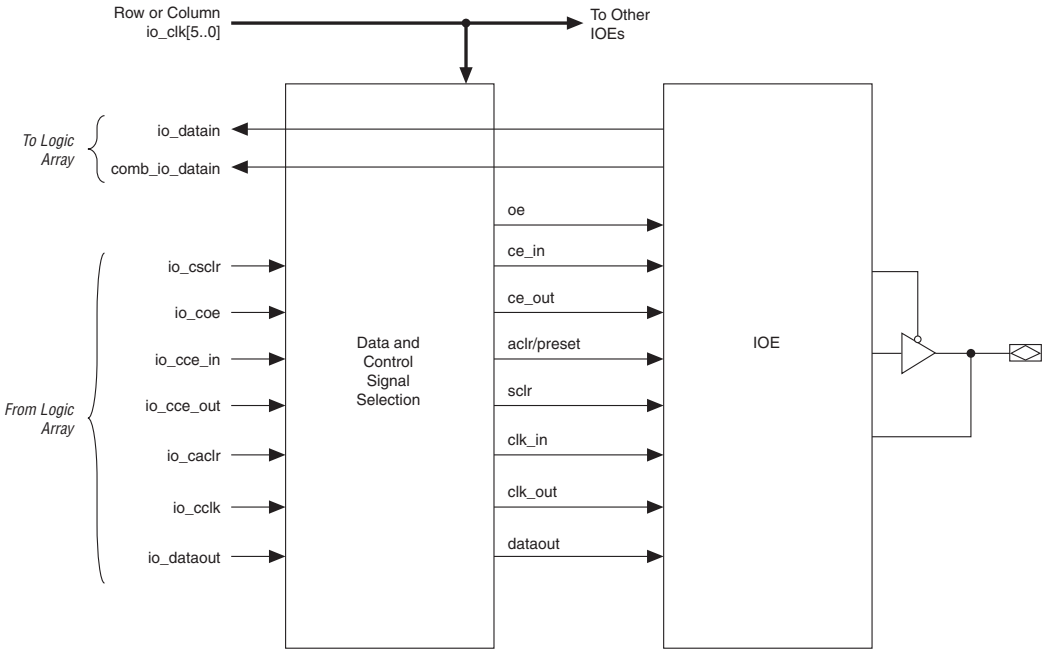
Notes to Figure 2–28:

(1) The 21 data and control signals consist of three data out lines, `io_dataout[2..0]`, three output enables, `io_coe[2..0]`, three input clock enables, `io_cce_in[2..0]`, three output clock enables, `io_cce_out[2..0]`, three clocks, `io_cclk[2..0]`, three asynchronous clear signals, `io_caclr[2..0]`, and three synchronous clear signals, `io_csclr[2..0]`.

(2) Each of the three IOEs in the row I/O block can have one `io_datain` input (combinatorial or registered) and one `comb_io_datain` (combinatorial) input.

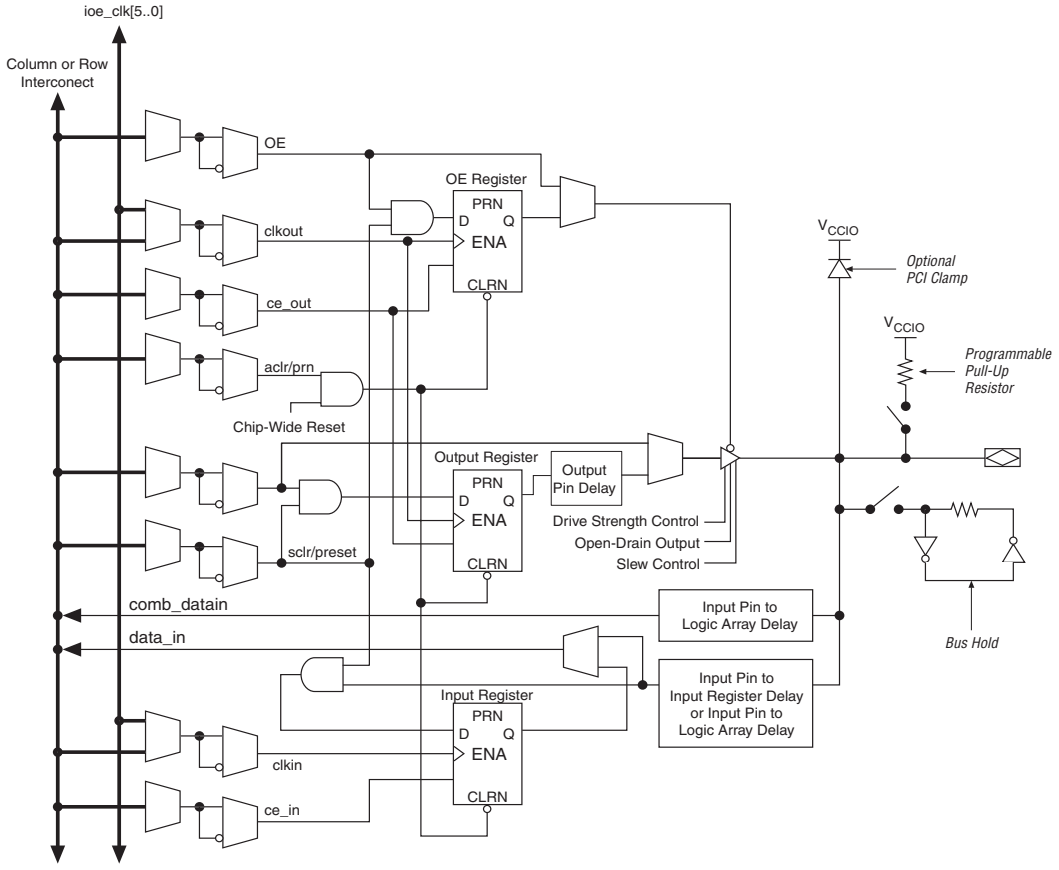
The pin's datain signals can drive the logic array. The logic array drives the control and data signals, providing a flexible routing resource. The row or column IOE clocks, `io_clk[5..0]`, provide a dedicated routing resource for low-skew, high-speed clocks. The global clock network generates the IOE clocks that feed the row or column I/O regions (see "Global Clock Network and Phase-Locked Loops" on page 2–29). Figure 2–30 illustrates the signal paths through the I/O block.

Figure 2–30. Signal Path through the I/O Block



Each IOE contains its own control signal selection for the following control signals: `oe`, `ce_in`, `ce_out`, `aclr/preset`, `sclr/preset`, `clk_in`, and `clk_out`. Figure 2–31 illustrates the control signal selection.

Figure 2–32. Cyclone IOE in Bidirectional I/O Configuration



The Cyclone device IOE includes programmable delays to ensure zero hold times, minimize setup times, or increase clock to output times.

A path in which a pin directly drives a register may require a programmable delay to ensure zero hold time, whereas a path in which a pin drives a register through combinatorial logic may not require the delay. Programmable delays decrease input-pin-to-logic-array and IOE input register delays. The Quartus II Compiler can program these delays

Slew-Rate Control

The output buffer for each Cyclone device I/O pin has a programmable output slew-rate control that can be configured for low noise or high-speed performance. A faster slew rate provides high-speed transitions for high-performance systems. However, these fast transitions may introduce noise transients into the system. A slow slew rate reduces system noise, but adds a nominal delay to rising and falling edges. Each I/O pin has an individual slew-rate control, allowing the designer to specify the slew rate on a pin-by-pin basis. The slew-rate control affects both the rising and falling edges.

Bus Hold

Each Cyclone device I/O pin provides an optional bus-hold feature. The bus-hold circuitry can hold the signal on an I/O pin at its last-driven state. Since the bus-hold feature holds the last-driven state of the pin until the next input signal is present, an external pull-up or pull-down resistor is not necessary to hold a signal level when the bus is tri-stated.

The bus-hold circuitry also pulls undriven pins away from the input threshold voltage where noise can cause unintended high-frequency switching. The designer can select this feature individually for each I/O pin. The bus-hold output will drive no higher than V_{CCIO} to prevent overdriving signals. If the bus-hold feature is enabled, the device cannot use the programmable pull-up option. Disable the bus-hold feature when the I/O pin is configured for differential signals.

The bus-hold circuitry uses a resistor with a nominal resistance (RBH) of approximately 7 kΩ to pull the signal level to the last-driven state. Table 4–15 on page 4–6 gives the specific sustaining current for each V_{CCIO} voltage level driven through this resistor and overdrive current used to identify the next-driven input level.

The bus-hold circuitry is only active after configuration. When going into user mode, the bus-hold circuit captures the value on the pin present at the end of configuration.

Programmable Pull-Up Resistor

Each Cyclone device I/O pin provides an optional programmable pull-up resistor during user mode. If the designer enables this feature for an I/O pin, the pull-up resistor (typically 25 kΩ) holds the output to the V_{CCIO} level of the output pin's bank. Dedicated clock pins do not have the optional programmable pull-up resistor.

Table 4–5. LVCMOS Specifications

Symbol	Parameter	Conditions	Minimum	Maximum	Unit
V_{CCIO}	Output supply voltage	—	3.0	3.6	V
V_{IH}	High-level input voltage	—	1.7	4.1	V
V_{IL}	Low-level input voltage	—	–0.5	0.7	V
V_{OH}	High-level output voltage	V_{CCIO} = 3.0, I_{OH} = –0.1 mA	V_{CCIO} – 0.2	—	V
V_{OL}	Low-level output voltage	V_{CCIO} = 3.0, I_{OL} = 0.1 mA	—	0.2	V

Table 4–6. 2.5-V I/O Specifications

Symbol	Parameter	Conditions	Minimum	Maximum	Unit
V_{CCIO}	Output supply voltage	—	2.375	2.625	V
V_{IH}	High-level input voltage	—	1.7	4.1	V
V_{IL}	Low-level input voltage	—	–0.5	0.7	V
V_{OH}	High-level output voltage	I_{OH} = –0.1 mA	2.1	—	V
		I_{OH} = –1 mA	2.0	—	V
		I_{OH} = –2 to –16 mA *(11)*	1.7	—	V
V_{OL}	Low-level output voltage	I_{OL} = 0.1 mA	—	0.2	V
		I_{OH} = 1 mA	—	0.4	V
		I_{OH} = 2 to 16 mA *(11)*	—	0.7	V

Table 4–7. 1.8-V I/O Specifications

Symbol	Parameter	Conditions	Minimum	Maximum	Unit
V_{CCIO}	Output supply voltage	—	1.65	1.95	V
V_{IH}	High-level input voltage	—	0.65 × V_{CCIO}	2.25 *(12)*	V
V_{IL}	Low-level input voltage	—	–0.3	0.35 × V_{CCIO}	V
V_{OH}	High-level output voltage	I_{OH} = –2 to –8 mA *(11)*	V_{CCIO} – 0.45	—	V
V_{OL}	Low-level output voltage	I_{OL} = 2 to 8 mA *(11)*	—	0.45	V

Table 4–16. Cyclone Device Capacitance *Note (14)*

Symbol	Parameter	Typical	Unit
C_{IO}	Input capacitance for user I/O pin	4.0	pF
C_{LVDS}	Input capacitance for dual-purpose LVDS/user I/O pin	4.7	pF
C_{VREF}	Input capacitance for dual-purpose V_{REF}/user I/O pin.	12.0	pF
C_{DPCLK}	Input capacitance for dual-purpose DPCLK/user I/O pin.	4.4	pF
C_{CLK}	Input capacitance for CLK pin.	4.7	pF

Notes to Tables 4–1 through 4–16:

(1) Refer to the *Operating Requirements for Altera Devices Data Sheet*.

(2) Conditions beyond those listed in Table 4–1 may cause permanent damage to a device. Additionally, device operation at the absolute maximum ratings for extended periods of time may have adverse affects on the device.

(3) Minimum DC input is –0.5 V. During transitions, the inputs may undershoot to –2.0 V or overshoot to 4.6 V for input currents less than 100 mA and periods shorter than 20 ns.

(4) Maximum V_{CC} rise time is 100 ms, and V_{CC} must rise monotonically.

(5) All pins, including dedicated inputs, clock, I/O, and JTAG pins, may be driven before V_{CCINT} and V_{CCIO} are powered.

(6) Typical values are for T_A = 25° C, V_{CCINT} = 1.5 V, and V_{CCIO} = 1.5 V, 1.8 V, 2.5 V, and 3.3 V.

(7) V_I = ground, no load, no toggling inputs.

(8) This value is specified for normal device operation. The value may vary during power-up. This applies for all V_{CCIO} settings (3.3, 2.5, 1.8, and 1.5 V).

(9) R_{CONF} is the measured value of internal pull-up resistance when the I/O pin is tied directly to GND. R_{CONF} value will be lower if an external source drives the pin higher than V_{CCIO}.

(10) Pin pull-up resistance values will lower if an external source drives the pin higher than V_{CCIO}.

(11) Drive strength is programmable according to values in *Cyclone Architecture* chapter in the *Cyclone Device Handbook*.

(12) Overdrive is possible when a 1.5 V or 1.8 V and a 2.5 V or 3.3 V input signal feeds an input pin. Turn on "Allow voltage overdrive" for LVTTL/LVCMOS input pins in the Assignments > Device > Device and Pin Options > Pin Placement tab when a device has this I/O combination. However, higher leakage current is expected.

(13) The Cyclone LVDS interface requires a resistor network outside of the transmitter channels.

(14) Capacitance is sample-tested only. Capacitance is measured using time-domain reflections (TDR). Measurement accuracy is within ±0.5 pF.

Internal timing parameters are specified on a speed grade basis independent of device density. Tables 4–25 through 4–28 show the internal timing microparameters for LEs, IOEs, TriMatrix memory structures, DSP blocks, and MultiTrack interconnects.

Table 4–25. LE Internal Timing Microparameters

Symbol	-6		-7		-8		Unit
	Min	Max	Min	Max	Min	Max	
t_{SU}	29	—	33	—	37	—	ps
t_{H}	12	—	13	—	15	—	ps
t_{CO}	—	173	—	198	—	224	ps
t_{LUT}	—	454	—	522	—	590	ps
t_{CLR}	129	—	148	—	167	—	ps
t_{PRE}	129	—	148	—	167	—	ps
t_{CLKHL}	1,234	—	1,562	—	1,818	—	ps

Table 4–26. IOE Internal Timing Microparameters

Symbol	-6		-7		-8		Unit
	Min	Max	Min	Max	Min	Max	
t_{SU}	348	—	400	—	452	—	ps
t_{H}	0	—	0	—	0	—	ps
t_{CO}	—	511	—	587	—	664	ps
$t_{PIN2COMBOUT\_R}$	—	1,130	—	1,299	—	1,469	ps
$t_{PIN2COMBOUT\_C}$	—	1,135	—	1,305	—	1,475	ps
$t_{COMBIN2PIN\_R}$	—	2,627	—	3,021	—	3,415	ps
$t_{COMBIN2PIN\_C}$	—	2,615	—	3,007	—	3,399	ps
t_{CLR}	280	—	322	—	364	—	ps
t_{PRE}	280	—	322	—	364	—	ps
t_{CLKHL}	1,234	—	1,562	—	1,818	—	ps

Table 4–44. Cyclone I/O Standard Output Delay Adders for Slow Slew Rate on Column Pins (Part 2 of 2)

I/O Standard		-6 Speed Grade		-7 Speed Grade		-8 Speed Grade		Unit
		Min	Max	Min	Max	Min	Max	
1.5-V LVTTL	2 mA	—	6,789	—	7,807	—	8,825	ps
	4 mA	—	5,109	—	5,875	—	6,641	ps
	8 mA	—	4,793	—	5,511	—	6,230	ps
SSTL-3 class I		—	1,390	—	1,598	—	1,807	ps
SSTL-3 class II		—	989	—	1,137	—	1,285	ps
SSTL-2 class I		—	1,965	—	2,259	—	2,554	ps
SSTL-2 class II		—	1,692	—	1,945	—	2,199	ps
LVDS		—	802	—	922	—	1,042	ps

Table 4–45. Cyclone I/O Standard Output Delay Adders for Slow Slew Rate on Row Pins (Part 1 of 2)

I/O Standard		-6 Speed Grade		-7 Speed Grade		-8 Speed Grade		Unit
		Min	Max	Min	Max	Min	Max	
LVCMOS	2 mA	—	1,800	—	2,070	—	2,340	ps
	4 mA	—	1,311	—	1,507	—	1,704	ps
	8 mA	—	945	—	1,086	—	1,228	ps
	12 mA	—	807	—	928	—	1,049	ps
3.3-V LVTTL	4 mA	—	1,831	—	2,105	—	2,380	ps
	8 mA	—	1,484	—	1,705	—	1,928	ps
	12 mA	—	973	—	1,118	—	1,264	ps
	16 mA	—	1,012	—	1,163	—	1,315	ps
	24 mA	—	838	—	963	—	1,089	ps
2.5-V LVTTL	2 mA	—	2,747	—	3,158	—	3,570	ps
	8 mA	—	1,757	—	2,019	—	2,283	ps
	12 mA	—	1,763	—	2,026	—	2,291	ps
	16 mA	—	1,623	—	1,865	—	2,109	ps
1.8-V LVTTL	2 mA	—	5,506	—	6,331	—	7,157	ps
	8 mA	—	4,220	—	4,852	—	5,485	ps
	12 mA	—	4,008	—	4,608	—	5,209	ps
1.5-V LVTTL	2 mA	—	6,789	—	7,807	—	8,825	ps
	4 mA	—	5,109	—	5,875	—	6,641	ps
	8 mA	—	4,793	—	5,511	—	6,230	ps
3.3-V PCI		—	923	—	1,061	—	1,199	ps

Table 4–52. Cyclone PLL Specifications (Part 2 of 2)

Symbol	Parameter	Min	Max	Unit
f_{OUT} (to global clock)	PLL output frequency (-6 speed grade)	15.625	405	MHz
	PLL output frequency (-7 speed grade)	15.625	320	MHz
	PLL output frequency (-8 speed grade)	15.625	275	MHz
t_{OUT} DUTY	Duty cycle for external clock output (when set to 50%)	45.00	55	%
t_{JITTER} *(1)*	Period jitter for external clock output	—	±300 *(2)*	ps
t_{LOCK} *(3)*	Time required to lock from end of device configuration	10.00	100	µs
f_{VCO}	PLL internal VCO operating range	500.00	1,000	MHz
-	Minimum areset time	10	—	ns
N, G0, G1, E	Counter values	1	32	integer

Notes to Table 4–52:

(1) The t_{JITTER} specification for the `PLL[2..1]_OUT` pins are dependent on the I/O pins in its V_{CCIO} bank, how many of them are switching outputs, how much they toggle, and whether or not they use programmable current strength or slow slew rate.

(2) $f_{OUT} \geq 100$ MHz. When the PLL external clock output frequency (f_{OUT}) is smaller than 100 MHz, the jitter specification is 60 mUI.

(3) $f_{IN/N}$ must be greater than 200 MHz to ensure correct lock detect circuit operation below –20 C. Otherwise, the PLL operates with the specified parameters under the specified conditions.